Unit in mm

## TOSHIBA TRANSISTOR SILICON NPN TRIPLE DIFFUSED TYPE

# 2 S D 5 2 5

#### POWER AMPLIFIER APPLICATIONS

• High Breakdown Voltage : V<sub>CEO</sub>=100V

• Low Collector Saturation Voltage: VCE (sat) = 2.0V (Max.)

• Complementary to 2SB595.

 Recommend for 30W High Fidelity Audio Frequency Amplifier Output Stage.

## MAXIMUM RATINGS (Tc = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	$v_{CBO}$	100 ( //	$\langle \hat{\mathbf{v}} \rangle$
Collector-Emitter Voltage	$v_{CEO}$	100	$\sqrt{\mathbf{v}}$
Emitter-Base Voltage	$v_{\mathrm{EBO}}$	5	V
Collector Current	$I_{\mathbf{C}}$	(5)	A
Base Current	$I_{\mathbf{B}}$	0.5	A /
Collector Power Dissipation (Tc=25°C)	PC	40	W
Junction Temperature	Tj	150	°C )
Storage Temperature Range	T <sub>stg</sub>	-55~150	,c\

10.3MAX, \$3.6 ± 0.2 1.5MAX. 0.76 1.5MAX. 0.76 1.5MAX. 0.76

2. COLLECTOR (HEAT SINK)
3. EMITTER

 JEDEC
 TO-220AB

 EIAJ
 SC-46

 TOSHIBA
 2-10A1A

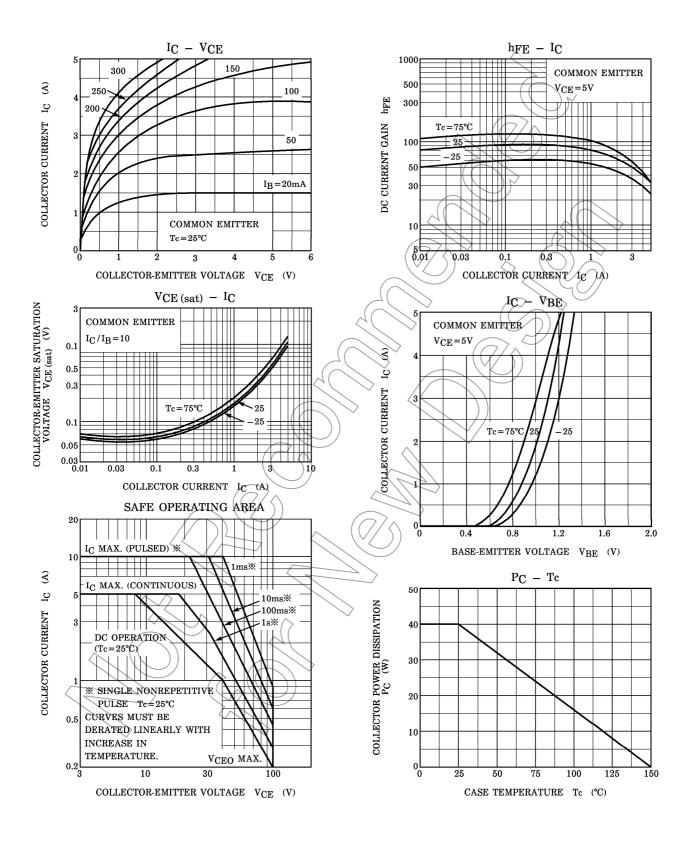
Weight: 1.9g (Typ.)

## ELECTRICAL CHARACTERISTICS (Tc = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	ICBO	$V_{CB} = 100V, I_{E} = 0$		_	100	$\mu$ <b>A</b>
Emitter Cut-off Current	$\widetilde{\mathrm{I}_{\mathrm{EBO}}}$	$V_{EB} = 5V, I_C = 0$			1	mA
Collector-Emitter Breakdown Voltage	V (BR) CEO	$I_{\rm C}$ =50mA, $I_{\rm B}$ =0	100	-	1	V
DC Current Gain	hFE (1) (Note)	$V_{CE} = 5V$ , $I_{C} = 1A$	40	1	240	
hFE	$h_{FE(2)}$	$V_{CE}=5V$ , $I_{C}=4A$	20		1	
Collector Emitter Saturation Voltage	VCE (sat)	$^{\prime}$ I <sub>C</sub> =4A, I <sub>B</sub> =0.4A	_	_	2.0	V
Base-Emitter Voltage	$\langle v_{ m BE} \rangle$	$V_{CE}=5V$ , $I_{C}=1A$	_	_	1.5	V
Transition Frequency	T	$V_{CE}=5V$ , $I_{C}=1A$	_	12	_	MHz
Collector Output Capacitance	$C_{ob}$	$V_{CB} = 10V, I_{E} = 0, f = 1MHz$	_	100	_	pF

Note :  $h_{FE(1)}$  Classification  $R:40\sim80$ ,  $O:70\sim140$ ,  $Y:120\sim240$ 

1 2001-05-24



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